

## **LISTING OF CLAIMS**

1. (previously presented) A memory system comprising:
  - a first memory array including a first plurality of memory cells;
  - a first decoder circuit for selecting ones of said first plurality of memory cells;
  - a first sensing circuit to detect content of said selected ones of said first plurality of memory cells using a first sensing mode;
  - a second memory array including a second plurality of memory cells;
  - a second decoder circuit for selecting ones of said second plurality of memory cells; and
  - a second sensing circuit to detect content of said selected ones of said second plurality of memory cells using a second sensing mode.
2. (previously presented) The memory system of claim 1 wherein the first and second plurality of memory cells are arranged in segments.
3. (previously presented) The memory system of claim 2 wherein the segments of said first plurality of memory cells are a first size and the segments of said second plurality of memory cells are a second size.
4. (previously presented) The memory system of claim 1 wherein the first plurality of memory cells store said content therein as multilevel content, and said second plurality of memory cells store said content therein as single level content.
5. (previously presented) The memory system of claim 1 wherein the first plurality of memory cells store said content therein as multilevel content, and said second plurality of memory cells store said content therein as multilevel content.
6. (previously presented) The memory system of claim 1, wherein said first memory array stores data and said second memory array stores code.
7. (previously presented) The memory system of claim 6 wherein said first sensing mode is a voltage sensing mode, and said second sensing mode is a current sensing mode.

8. (previously presented) The memory system of claim 6 where said first sensing mode is a current sensing mode, and said second sensing mode is a voltage sensing mode.
9. (previously presented) The memory system of claim 1 further comprising:  
a third memory array including a third plurality of memory cells;  
a third decoder circuit for selecting a portion of said third plurality of memory cells; and  
a third sensing circuit to detect using one of said first and second sensing modes, content of said selected portion of said third plurality of memory cells,  
wherein said second plurality of memory cells store said content therein using multilevel storage, and the third plurality of memory cells stores said content therein using single level storage.
10. (previously presented) The memory system of claim 9 wherein the first plurality of memory cells store data, and said second and third plurality of memory cells store code.
11. (previously presented) The memory system of claim 9 wherein the first plurality of memory cells store said content therein as multilevel content.
12. (previously presented) The memory system of claim 9 wherein the first plurality of memory cells store said content therein as single level content.
13. (previously presented) The memory system of claim 9 further comprising a tag bit array including a plurality of tag bit cells.
14. (previously presented) The memory system of claim 13 wherein each tag bit cell stores an indication of the content of an associated group of said first, second, and third plurality of memory cells.
15. (previously presented) The memory system of claim 13 further comprising:  
a fourth sensing circuit to detect a tag bit corresponding to said selected ones of said first,

second, or third plurality of memory cells to control said first and second sensing modes.

16 – 21. (cancelled)

22. (previously presented) A memory system comprising:  
a first memory array including a first plurality of memory cells;  
a first decoder circuit for selecting ones of said first plurality of memory cells;  
a second memory array including a second plurality of memory cells;  
a second decoder circuit for selecting ones of said second plurality of memory cells; and  
a sensing circuit to selectively detect content of said selected ones of said first plurality of memory cells using a first sensing mode and content of said selected ones of said second plurality of memory cells using a second sensing mode.

23. (previously presented) The memory system of claim 22 wherein the first and second plurality of memory cells are arranged in segments.

24. (previously presented) The memory system of claim 23 wherein the segments of said first plurality of memory cells are a first size and the segments of said second plurality of memory cells are a second size.

25. (previously presented) The memory system of claim 22 wherein the sensing circuit is configurable.

26. (previously presented) The memory system of claim 25 wherein the sensing circuit is configurable to switch between the first and second sensing modes.

27. (previously presented) The memory system of claim 25 wherein the sensing circuit is configurable to switch between a high speed sensing mode and a low speed sensing mode.

28. (previously presented) The memory system of claim 25 wherein the sensing circuit is configurable to switch between a multilevel sensing mode and a single level sensing mode.

29. (previously presented) The memory system of claim 22 wherein the first plurality of memory cells store multilevel content, the number of bits stored per cell being configurable, the sensing circuit being configurable to the configurable number of bits of content stored in said first plurality of memory cells.

30. (previously presented) The memory system of claim 22 wherein the sensing circuit comprises:

- a sensing mode configuration circuit coupled to selected ones of the first and second plurality of memory cells to detect content stored in said selected memory cells in said first or second sensing modes;

- a first transistor of the first type including first and second terminals with a channel therebetween, and a gate for controlling current in said channel and coupled to the sensing mode configuration circuit, said first terminal being coupled to a supply voltage;

- a current source including a first terminal coupled to the second terminal of the first transistor of the first type and a second terminal coupled to ground, a current source providing a bias current; and

- a comparator for comparing the voltage on said second terminal of the first transistor of the first type and a reference voltage, and including an output indicative of said comparison.

31. (previously presented) The memory system of claim 30 wherein the sensing mode configuration circuit comprises:

- a first transistor of a second type including first and second terminals with a channel therebetween, and a gate for controlling current in said channel, the second terminal being coupled to one of the selected ones of the first or second plurality of memory cells and coupled to the gate of the first transistor of the first type;

- a first switch including a first terminal coupled to a supply voltage and including a second terminal coupled to the first terminal of the first transistor of the second type to selectively couple the supply voltage to said first transistor of the second type in said first sensing mode;

a second switch including a first terminal coupled to the first terminal of the first transistor of the second type, and including a second terminal coupled to the gate of the first transistor of the second type to selectively couple said first terminal of the first transistor of the second type to said gate in said first sensing mode;

a third switch including a first terminal coupled to said selected one of the memory cells and including a second terminal coupled to a ground terminal, to selectively ground said selected memory cell in said first sensing mode;

a fourth switch including a first terminal coupled to the first terminal of the first transistor of the second type and including a second terminal coupled to said ground terminal to selectively couple said first terminal to said ground terminal in said second sensing mode;

a fifth switch including a first terminal coupled to the gate of said first transistor of the second type and including a second terminal coupled to a bias voltage terminal to selectively couple said bias voltage terminal to said gate in said second sensing mode; and

a sixth switch including a first terminal coupled to the supply voltage, and including a second terminal coupled to the selected memory cell to selectively couple said memory cell to said supply voltage in said second sensing mode.

32. (previously presented) The memory system of claim 22 further comprising:

a third memory array including a third plurality of memory cells;

a third decoder circuit for selecting ones of said third plurality of memory cells,

wherein the sensing circuit further selectively detects using said second sensing mode content of said selected ones of said third plurality of memory cells,

wherein said second plurality of memory cells store said content therein using multilevel storage and the third plurality of memory cells stores said content therein using single level storage.

33. (previously presented) The memory system of claim 32 wherein the sensing circuit is configurable.

34. (previously presented) The memory system of claim 33 wherein the sensing circuit is configurable to switch between the first and second sensing modes.

35. (previously presented) The memory system of claim 32 wherein the first, second, and third pluralities of memory cells are arranged in segments.

36. (previously presented) The memory system of claim 35 wherein the segments of said first plurality of memory cells are a first size, the segments of said second plurality of memory cells are a second size, and the segments of said third plurality of memory cells are a third size.

37. (previously presented) A memory system comprising:

- a first memory array including a first plurality of memory cells;
- a first decoder circuit for selecting a portion of said first plurality of memory cells;
- a tag bit memory for storing tag bit indicators of content stored in corresponding cells of the first plurality of memory cells;

- a tag bit sensing circuit to detect a selected tag bit indicator corresponding to selected ones of said first plurality of memory cells;

- a first sensing circuit to selectively detect using a first sensing mode or a second sensing mode content of said selected portion of said first plurality of memory cells, the first and second sensing modes being determined by the selected tag bit corresponding to the selected memory cells;

- a content addressable memory including a second plurality of memory cells;
- a second decoder circuit for selecting a portion of said second plurality of memory cells of said content addressable memory; and

- a second sensing circuit to detect content of said selected portion of said second plurality of memory cells.

38. (previously presented) The memory system of claim 37 wherein the first plurality of memory cells are arranged in segments.

39. (previously presented) The memory system of claim 38 wherein the segments of a first portion of said first plurality of memory cells are a first size and the segments of a second portion of said first plurality of memory cells are a second size.

40. (previously presented) The memory system of claim 37 wherein the first sensing circuit is configurable.

41. (previously presented) The memory system of claim 37 further comprising:  
an extension array comprising a third plurality of memory cells, the third plurality of memory cells storing information related to a corresponding portion of said first plurality of memory cells;  
an extension decoder circuit for selecting ones of said third plurality of memory cells; and  
an extension sensing circuit to detect content of said selected ones of said third plurality of memory cells.

42. (previously presented) The memory system of claim 41 further comprising:  
a second extension array including a fourth plurality of memory cells for storing information related to a corresponding portion of the second plurality of memory cells related to the content addressable memory; and  
a second extension decoder for selecting a portion of the fourth plurality of memory cells, wherein the extension sensing circuit detects content of selected portion of said fourth plurality of memory cells.

43. (previously presented) The memory system of claim 40 wherein the configurable sense circuit comprises:

a sensing mode configuration circuit coupled to the selected ones of the first or second plurality of memory cells to detect content stored in said selected memory cells in said first or second sensing modes;

a first transistor of a first type including first and second terminals with a channel therebetween, and a gate for controlling current in said channel and coupled to the sensing mode configuration circuit, said first terminal being coupled to a supply voltage;

a current source including a first terminal coupled to the second terminal of the first transistor of the first type and a second terminal coupled to ground, the current source providing a bias current; and

a comparator for comparing the voltage on said second terminal of the first transistor of the first type and a reference voltage and including an output indicative of said comparison.

44. (previously presented) The memory system of claim 43 wherein the sensing mode configuration circuit comprises:

a first transistor of a second type including first and second terminals with a channel therebetween, and a gate for controlling current in said channel, the second terminal being coupled to one of the selected ones of the first or second plurality of memory cells and coupled to the gate of the first transistor of the first type;

a first switch including a first terminal coupled to a supply voltage and including a second terminal coupled to the first terminal of the first transistor of the second type to selectively couple the supply voltage to said first transistor of the second type in said first sensing mode;

a second switch including a first terminal coupled to the first terminal of the first transistor of the second type, and including a second terminal coupled to the gate of the first transistor of the second type to selectively couple said first terminal of the first transistor of the second type to said gate in said first sensing mode;

a third switch including a first terminal coupled to said selected one of the memory cells and including a second terminal coupled to a ground terminal, to selectively ground said selected memory cell in said first sensing mode;

a fourth switch including a first terminal coupled to the first terminal of the first transistor of the second type and including a second terminal coupled to said ground terminal to selectively couple said first terminal to said ground terminal in said second sensing mode;

a fifth switch including a first terminal coupled to the gate of said first transistor of the second type and including a second terminal coupled to a bias voltage terminal to selectively couple said bias voltage terminal to said gate in said second sensing mode; and

a sixth switch including a first terminal coupled to the supply voltage, and including a second terminal coupled to the selected memory cell to selectively couple said memory cell to said supply voltage in said second sensing mode.

45 – 51. (cancelled)



52. (previously presented) A memory system comprising:  
a plurality of memory arrays, each memory array including a plurality of memory cells for storing content therein, a decoder circuit for selecting ones of said plurality of memory cells, and a sensing circuit to selectively detect content of said selected ones of said plurality of memory cells; and  
a memory controller to perform a first memory operation on a first one of said memory arrays and perform a second memory operation on a second one of said memory arrays concurrently, said first and second ones of the memory arrays storing first and second type of content, respectively.
53. (previously presented) The memory system of claim 52 wherein said first and second memory operations are selected from one of program, erase, and read.
54. (previously presented) The memory system of claim 53 wherein said first and second types of content are selected from the group of code and data.
55. (previously presented) The memory system of claim 52 wherein said first and second types of content are selected from the group of code and data.
56. (previously presented) The memory system of claim 52 further comprising an extension array, wherein said memory controller performs said first memory function on a first one of said memory arrays and performs a third function on said extension memory array.
57. (previously presented) The memory system of claim 52 further comprising a content addressable memory, and wherein said memory controller performs said first memory operation and performs a third memory operation on said content addressable memory concurrently.
58. (previously presented) The memory system of claim 52 wherein the first memory operation is programming, the first one of said memory arrays stores data, the second memory operation is erasing and the second one of the memory arrays stores code.

59. (previously presented) The memory system of claim 52 wherein the first memory operation is programming, the first one of said memory arrays stores data, the second memory operation is programming, and the second one of the memory arrays stores code.

60. (previously presented) A memory system comprising:  
a plurality of memory arrays, each memory array including a plurality of memory cells for storing content therein, a decoder circuit for selecting ones of said plurality of said memory cells, and a multi-mode sensing circuit to detect the content of said selected ones of said plurality of memory cells; and

an interface controller to perform interface logic depending on the selected memory array or depending on an external interface.

61. (previously presented) The memory system of claim 60 further including an IO driver controller.

62. (previously presented) The memory system of claim 60 further including a general purpose memory controller.

63. (previously presented) A memory system comprising:  
a plurality of memory arrays, each memory array including a plurality of memory cells for storing content therein, a decoder circuit for selecting ones of said plurality of said memory cells, and a sensing circuit to detect the content of said selected ones of said plurality of memory cells;

an interface controller to perform interface logic depending on the selected memory array or depending on an external interface; and

a general purpose memory controller handles production and/or screen testing.

64. (previously presented) A memory system comprising:  
a plurality of memory arrays, each memory array including a plurality of memory cells for storing content therein, a decoder circuit for selecting ones of said plurality of memory cells,

and a multi-mode sensing circuit to selectively detect content of said selected ones of said plurality of memory cells; and

an IO driver controller to perform an appropriate IO driver interface depending on the selected memory array or depending on an external interface.

65. (previously presented) The memory system of claim 64 further including an interface controller.

66. (previously presented) The memory system of claim 64 further including a general purpose memory controller.

67. (previously presented) A memory system comprising:  
a plurality of memory arrays, each memory array including a plurality of memory cells for storing content therein, a decoder circuit for selecting ones of said plurality of memory cells, and a sensing circuit to selectively detect content of said selected ones of said plurality of memory cells;

an IO driver controller to perform an appropriate IO driver interface depending on the selected memory array or depending on an external interface; and

a general purpose memory controller handles production and/or screen testing.

68. (previously presented) A memory system comprising:  
a content addressable memory including a first plurality of multilevel memory cells;  
a decoder circuit for selecting ones of said first plurality of memory cells of said content addressable memory; and

a sensing circuit to detect content of said selected ones of said first plurality of memory cells.

69. (previously presented) The memory system of claim 68 further comprising:  
a tag bit memory for storing tag bit indicators of content stored in corresponding ones of the first plurality of memory cells.

70. (previously presented) The memory system of claim 69 further comprising:  
a tag bit sensing circuit to detect a selected tag bit indicator corresponding to selected ones of said first plurality of memory cells.
71. (previously presented) The memory system of claim 68 further comprising:  
a second memory array including a second plurality of memory cells;  
a second decoder circuit for selecting ones of said second plurality of memory cells[[:]].
72. (previously presented) The memory system of claim 71 further comprising:  
a second sensing circuit to selectively detect using a first or second sensing mode content of said selected ones of said second plurality of memory cells, the first and second sensing mode being determined by the selected tag bit corresponding to the selected memory cells.
73. (previously presented) A memory system comprising:  
an extension array comprising a first plurality of memory cells, the first plurality of memory cells being configurable to a number of memory levels;  
an extension decoder circuit for selecting ones of said first plurality of memory cells; and  
an extension sensing circuit to detect content of said selected ones of said first plurality of memory cells.
74. (previously presented) The memory system of claim 73 wherein the sensing circuit configures the sensing mode according to the configurability of memory cells.
75. (previously presented) The memory system of claim 73 further comprising:  
a tag bit memory for storing tag bit indicators of content stored in corresponding ones of the first plurality of memory cells.
76. (previously presented) The memory system of claim 75 further comprising:  
a tag bit sensing circuit to detect a selected tag bit indicator corresponding to selected ones of said first plurality of memory cells.

77. (previously presented) A memory system comprising:  
an array comprising a first plurality of memory cells, the first plurality of memory cells being configurable to a number of memory levels and arranged in a plurality of array sectors, a security key stored for each array sector;  
a decoder circuit for selecting ones of said first plurality of memory cells; and  
a multi-mode sensing circuit to detect content of said selected ones of said first plurality of memory cells.
78. (previously presented) A memory system comprising:  
an array comprising a first plurality of memory cells, the first plurality of memory cells being configurable to a number of memory levels and arranged in a plurality of array sectors, a security key stored for each array sector;  
a decoder circuit for selecting ones of said first plurality of memory cells;  
a sensing circuit to detect content of said selected ones of said first plurality of memory cells; and  
a sensing circuit to sense said security key.
79. (previously presented) A memory system comprising:  
an array comprising a first plurality of memory cells, the first plurality of memory cells being configurable to a number of memory levels and arranged in a plurality of array sectors, a security measure stored for each array sector;  
a decoder circuit for selecting ones of said first plurality of memory cells; and  
a multi-mode sensing circuit to detect content of said selected ones of said first plurality of memory cells.
80. (previously presented) A memory system comprising:  
an array comprising a first plurality of memory cells, the first plurality of memory cells being configurable to a number of memory levels and arranged in a plurality of array sectors, a security measure stored for each array sector;  
a decoder circuit for selecting ones of said first plurality of memory cells; and  
a sensing circuit to detect content of said selected ones of said first plurality of memory

cells and

wherein the security measure comprises disabling a security memory area.

81. (previously presented) A memory system comprising:

an array comprising a first plurality of memory cells, the first plurality of memory cells being configurable to a number of memory levels and arranged in a plurality of array sectors, a security measure stored for each array sector;

a decoder circuit for selecting ones of said first plurality of memory cells; and

a sensing circuit to detect content of said selected ones of said first plurality of memory cells and

wherein the security measure comprises altering a security memory area.

82. (previously presented) A memory system comprising:

a memory comprising a plurality of memory arrays, each memory array including a plurality of memory cells for storing content therein,

a first one of said memory arrays executing a first memory operation and a second one of said memory arrays executing a second memory operation concurrently,

said first and second memory arrays storing first and second type of content, respectively.

83. (previously presented) The memory system of claim 82 wherein the memory is monolithic.

84. (previously presented) The memory system of claim 82 wherein the first memory operation is programming, the first one of said memory arrays stores data, the second memory operation is erasing and the second one of the memory arrays stores code.

85. (previously presented) The memory system of claim 82 wherein the first memory operation is programming, the first one of said memory arrays stores data, the second memory operation is programming, and the second one of the memory arrays stores code.

86. (previously presented) The memory system of claim 62 wherein the general purpose

memory controller handles production and/or screen testing.

87. (previously presented) The memory system of claim 66 wherein the general purpose memory controller handles production and/or screen testing.

88. (previously presented) The memory system of claim 77 further including a sensing circuit to sense said security key.

89. (previously presented) The memory system of claim 79 wherein the security measure comprising disabling a security memory area.

90. (previously presented) The memory system of claim 79 wherein the security measure comprises altering a security memory area.

**STATUS OF THE APPLICATION**

- Claims 1-15, 22-44, and 52-90 have been allowed.
- Claims 16-22 are rejected as requiring further search and/or consideration.